

As an example, Fig. 4 shows the results obtained for the mixed-potential Green's functions in Fig. 3(a) obtained with (9), as compared with the Green's functions obtained using a standard Sommerfeld formulation (10) of the identical problem in Fig. 3(b). Fig. 4 shows the comparison for both the electric scalar potential and magnetic vector potential (analogous to the electric scalar potential, but not vanishing in the walls), when the source is placed at points A and B in Fig. 3, and as a function of the position of the observer point. As we observe, the agreement is excellent; therefore, validating the parallel-plate Green's functions computed with the new algorithm.

V. CONCLUSIONS

In this paper, a new and efficient technique for the convergence acceleration of a large class of series arising in electromagnetic problems has been presented. The technique can be viewed as the successive application of the integration-by-parts technique to discrete sequences; therefore, the given name of the "summation-by-parts technique."

The technique has been first applied to the numerical evaluation of a simple canonical series, showing that convergence is greatly enhanced, allowing to obtain very small relative errors with just a few operations. The technique described can be applied to many real electromagnetic problems and, in this paper, it has been used for the efficient numerical calculation of the parallel-plate mixed-potential Green's functions.

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Direct Extraction of Linear HBT-Model Parameters Using Nine Analytical Expression Blocks

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Abstract—A method to determine the heterojunction bipolar transistor (HBT) equivalent-circuit elements without numerical optimizations is presented. It is based on the extraction of nine analytical expressions, which are referred to here as "blocks." The model elements are extracted using certain blocks for some of them and three nonlinear equations derived from a combination of four expression blocks for some others. The base and collector resistances can be determined at each bias point. The method is validated treating the on-wafer HBTs.

Index Terms—Analytical method, heterojunction bipolar transistor, parameter extraction.

I. INTRODUCTION

An accurate parameter-extraction procedure of the linear equivalent circuit is crucial to optimize the device and circuit performances. Approaches that consist of reducing the number of unknown elements by using complementary characterizations for independently estimating as many heterojunction bipolar transistor (HBT) parameters as possible have been proposed [1]–[3]. Measurements of special test structures and geometrical and material parameters are needed in [1] to obtain some of the parasitic parameter values. The measurements of two separate test structures are proposed in [2] and [3] to determine the probe-pattern parasitic. The cutoff mode measurements are used in [2] to determine some of the HBTs' capacitances, and the equivalent circuit of the device biased to active mode is obtained using numerical optimizations. Analytical expressions and numerical optimizations are used in [3] and [4] and the information about the geometry device is used to evaluate the ratio μ between the extrinsic and intrinsic base-collector capacitances. Analytical extraction methods have been proposed in [5] and [6]. In [5], the method is based on the use of local fitting routines and certain assumptions. In [6], the S -parameters measured under open-collector condition are used to determine the extrinsic elements. An approach based on both empirical optimization and analytical evaluations is reported in [7]. Initial values of HBT parameters are estimated from dc and multibias S -parameter measurements and then used to achieve the evaluation of the HBT model elements by the impedance-block conditioned optimization. Finally, a procedure combining the analytical and optimization approaches was developed in [8], in which the influence of pad capacitances is discussed.

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We present a new analytical method of parameter extraction. It is based on the obtainment of suitable organization of combined Z -parameter analytical expressions. Each analytical expression is structured to obtain a polynomial function with ω as variable and whose coefficients depend only on the circuit elements. The polynomial functions are analyzed in order to choose the most adequate coefficients, referred to here as “blocks” ($b1$ – $b9$, as shown in Table I). The model elements are calculated using certain blocks for some of them and three non-linear equations for some others. In particular, the base and collector resistances considered bias independent in the previous methods can be obtained here at each bias point with the other HBT bias dependent elements. The parasitic inductances are determining taking into account the influence of the inductive terms due to other HBT parameters. The effect of base–contact impedance as modeled in [1] is very visible in low-frequency range and, therefore, its contribution is taken into account. The procedure is validated treating GaInP/GaAs and GaInP/InP HBTs. In this investigation, the procedure is applied to extract the circuit parameters of a GaInP/GaAs HBT.

II. THEORY OF PARAMETER-EXTRACTION PROCEDURE

The combined expressions of Z -parameters of the equivalent circuit shown in Fig. 1 can be expressed as follows without approximations:

$$Z_{11} - Z_{12} = Z_b + \frac{(Z_\pi + R_b)g_0 + j\omega C_{bc}R_b + j\omega C_c R_b A}{Y} + j\omega L_b \quad (1)$$

$$Z_{22} - Z_{12} = R_c + \frac{1}{Y} + j\omega L_c \quad (2)$$

$$Z_{12} - Z_{21} = \frac{g_m Z_\pi}{Y} \quad (3)$$

with $Z_\pi = (R_\pi)/(1 + j\omega R_\pi C_\pi)$, $C = (C_{bc}C_c)/(C_{bc} + C_c)$, $Y = j\omega(C_{bc} + C_c)(1 + j\omega C_{bc}R_b)A + g_0(1 + j\omega C_{bc}R_b)$, $A = 1 + (g_0 + g_m)Z_\pi$, and $g_m = g_{m0}e^{-j\omega\tau_d}$, where g_{m0} is the dc transconductance. The structured polynomial functions are obtained from (1)–(3) using the hypothesis summarized in Table II, and as shown in (4)–(12), at the bottom of this page, with $R_e = (R_\pi)/(1 + g_{m0}R_\pi)$

TABLE I
ANALYTICAL EXPRESSIONS OF THE BLOCKS. THE VALUES FOR $V_{CE} = 2$ V, $I_B = 150$ mA: $b1 = 55 \Omega$, $b2 = 1410^{-6}$ S, $b3 = 58.2 \Omega$, $b4 = 34$ fF, $b5 = 26 \Omega$, $b6 = 168$ pH, $b7 = 58.9$, $b8 = 20 \Omega$, $b9 = 58.2$ pH

$b1 = R_c + \frac{R_e C_\pi}{(C_{bc} + C_c)}$	$b2 = \frac{g_0}{g_{m0} R_\pi}$	$b3 = \frac{R_b C + R_e C_\pi}{(C_{bc} + C_c)}$
$b4 = C_{bc} + C_c$	$b5 = \frac{R_b C}{C_{bc}} + g_0 \frac{R_b R_e C_\pi}{(C_{bc} + C_c)}$	
$b6 = L_e + \frac{R_e C_\pi R_b C_{bc}}{(C_{bc} + C_c)}$	$b7 = g_{m0} R_\pi + 1$	
$b8 = R_E + R_e + \frac{R_b C_{bc}}{(g_{m0} R_\pi + 1)(C_{bc} + C_c)}$		
$b9 = \frac{R_e C_\pi}{C_{bc} + C_c} (R_e C_\pi + R_b C - \tau_d) - L_c$		

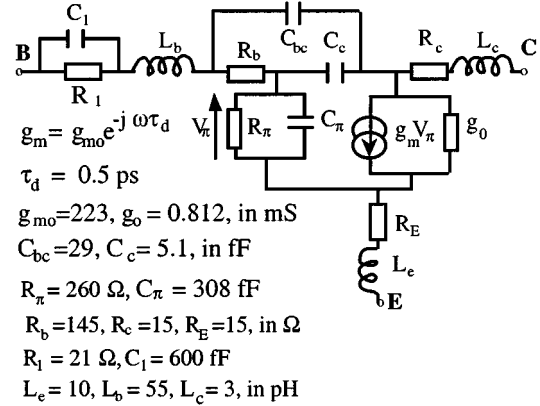


Fig. 1. HBT linear equivalent circuit.

III. EXTRACTION OF THE CIRCUIT PARAMETERS

The S -parameter measurements are performed from 0.3 to 40 GHz and converted to Z -parameters to determine R_1 , C_1 , and the nine blocks. The resistance R_E and the ideality factor N_E are extracted from block 8 measured at different emitter currents. The inductances

$$\text{Real}(Z_{22} - Z_{12}) = \frac{g_0}{(g_{m0} R_\pi + 1)^2 (C_{bc} + C_c)^2 \omega^2} + b1 - \frac{R_e C_\pi R_b C}{(C_{bc} + C_c)} (R_e C_\pi - \tau_d) \omega^2 \quad (4)$$

$$\text{Real}\left(\frac{1}{Z_{12} - Z_{21}}\right) = b2 - (C_{bc} + C_c) (R_e C_\pi + R_b C) \omega^2 \quad (5)$$

$$\text{Real}(Z_{21} - Z_{12}) = \frac{-g_0}{(g_{m0} R_\pi + 1) (C_{bc} + C_c)^2 \omega^2} + b3 + \tau_d \frac{R_b C (R_e C_\pi - \tau_d) \omega^2}{(C_{bc} + C_c)} \quad (6)$$

$$\text{Imag}\left(\frac{1}{Z_{12} - Z_{21}}\right) = b4\omega - \left[\tau_d (R_e C_\pi - \tau_d) + R_e C_\pi R_b C\right] (C_{bc} + C_c) \omega^3 \quad (7)$$

$$\text{Real}(Z_{11} - Z_{12}) = \frac{R_1}{1 + (R_1 C_1 \omega)^2} + b5 \quad (8)$$

$$\text{Imag}(Z_{12}) = g_0 \frac{[R_\pi (C_{bc} + C_c) - R_b C_{bc}]}{(g_{m0} R_\pi + 1)^2 (C_{bc} + C_c)^2} \frac{1}{\omega} + b6\omega - \left(\frac{R_e C_\pi R_b C_{bc}}{C_{bc} + C_c} + R_e R_b C\right) (R_e C_\pi - \tau_d) R_b C \omega^3 \quad (9)$$

$$\frac{-\text{Imag}(Z_{21})}{\text{Imag}(Z_{22} - Z_{12})} = b7 \frac{1 + [L_e (C_{bc} + C_c) + R_e C_\pi R_b C_{bc} - \tau_d (R_e C_\pi + R_b C - \tau_d)] \omega^2}{1 + [-L_c (g_{m0} R_\pi + 1) (C_{bc} + C_c) + R_\pi C_\pi (R_e C_\pi + R_b C - \tau_d)] \omega^2} \quad (10)$$

$$\text{Real}(Z_{12}) = b8 + \frac{R_b C_{bc} R_e C_\pi}{C_{bc} + C_c} (R_e C_\pi + R_b C - \tau_d) \omega^2 \quad (11)$$

$$-\omega \text{Imag}(Z_{22} - Z_{12}) = \frac{1}{(g_{m0} R_\pi + 1) (C_{bc} + C_c)} + b9 \omega^2 - b9 [(R_b C)^2 + (R_e C_\pi - \tau_d)^2] \omega^4 \quad (12)$$

TABLE II
HYPOTHESIS AND HYPOTHESIS NUMBER $H_i (i = 1 \text{ to } 4)$. AS AN EXAMPLE, (9)–(13) AND (16) ARE OBTAINED USING H_1 AND H_2 HYPOTHESIS

hypothesis	H_i
$g_0 R_e C_\pi \ll C_{bc} + C_c$	
$g_0 R_e C_\pi R_b C_{bc} \ll (C_{bc} + C_c)(R_e C_\pi + R_b C - \tau_d)$	H_1
$\frac{g_{m0} R_\pi}{g_{m0} R_\pi + 1} \approx 1, f \ll \frac{1}{2\pi\tau_d}, \frac{g_0 \tau_d}{g_{m0} R_\pi + 1} \ll C_{bc} + C_c$	H_2
$\frac{g_0 R_e C_\pi R_b C_{bc}}{(g_{m0} R_\pi + 1)(C_{bc} + C_c)^2} \ll R_e + R_E$	
$\frac{g_0 R_e R_b C}{(g_{m0} R_\pi + 1)(C_{bc} + C_c)} \ll R_e + R_E$	H_3
$\frac{R_e C_\pi + R_b C - \tau_d}{g_{m0} R_\pi + 1} \ll R_e C_\pi$	H_4
Equation (s)	eq.4 eqs. 5-9, 12 eq.10 eq.11
H_i used	H_1, H_2, H_4 H_1, H_2 H_1 H_1, H_2, H_3

are obtained taking into account the influence of the inductive terms. Blocks 2 and 7 are used to determine g_{m0} and g_0 . The parameters C_π , C_{bc} , C_c , R_b , R_c , and τ_d are obtained using three nonlinear equations. The pad capacitances (not shown in Fig. 1) are removed from measurements.

A. Determination of the Value of Each Block ($b_i, i = 1-9$)

The values of the nine blocks can be extracted using the frequency dependence of the left members in (4)–(12). Each block value is obtained using linear regression over an adequate frequency range (Table III). As an example, the values $b1$ and $b5$ are extracted using the frequency dependencies of $\text{Real}(Z_{22} - Z_{12})$ and $\text{Real}(Z_{11} - Z_{12})$, respectively [see Fig. 2(a) and (b)]. These results confirm the theoretical evolution described in (4) and (8). The first term of the right-hand-side expression in (4) describes the fast decrease of $\text{Real}(Z_{22} - Z_{12})$ in the low-frequency range. The second term has a constant value $b1$ over all frequencies $f b_{11} = 0.3 \text{ GHz} \ll f \ll f b_{12} = 254 \text{ GHz}$. Thereby $b1$ can be easily extracted. In Fig. 2(b), $\text{Real}(Z_{11} - Z_{12})$ decreases quickly for $f \leq 20 \text{ GHz}$ and becomes frequency independent for $f > 20 \text{ GHz}$. These experimental evolution is well described in (8) and allows us to extract $b5$.

B. Determination of R_1 , C_1 , R_E , and the Access Inductances

Fig. 2(b) and (8) are used to determine R_1 and C_1 as follows:

$$m_1 - b5 = \frac{R_1}{1 + (R_1 C_1 f_1)^2}$$

and

$$m_2 - b5 = \frac{R_1}{1 + (R_1 C_1 f_2)^2} \quad (13)$$

where m_1 and m_2 are the values of $\text{Real}(Z_{11} - Z_{12})$ corresponding to f_1 and f_2 , respectively. Frequencies f_1 and f_2 are chosen over a frequency range where the influence of the first term in (8) is important compared to that of the second term. Using (13), we have

$$R_1 = (m_1 - b5) \left(1 + \frac{1 - \frac{m_1 - b5}{m_2 - b5}}{\frac{m_1 - b5}{m_2 - b5} - \left(\frac{f_2}{f_1}\right)^2} \right)$$

TABLE III
FREQUENCY RANGE WHERE EACH BLOCK VALUE IS EXTRACTED

bi	frequency range
b1 $f > f_{b11} = \frac{1}{2\pi} \sqrt{\frac{g_0 / [(g_{m0} R_\pi + 1)^2 (C_{bc} + C_c)]}{R_c (C_{bc} + C_c) + R_e C_\pi}}$	
$f < f_{b12} = \frac{1}{2\pi} \sqrt{\frac{R_c (C_{bc} + C_c) + R_e C_\pi}{R_b C R_e C_p (R_e C_p - \tau_d)}}$	
b2 $f < f_{b2} = \frac{1}{2\pi} \sqrt{\frac{g_0 [g_{m0} R_\pi (C_{bc} + C_c) (R_e C_\pi + R_b C)]^{-1}}{g_0 [g_{m0} R_\pi (C_{bc} + C_c) (R_e C_\pi + R_b C)]^{-1}}}$	
b3 $f > f_{b31} = \frac{1}{2\pi} \sqrt{\frac{g_0 / [(g_{m0} R_\pi + 1)(C_{bc} + C_c)]}{R_e C_\pi + R_b C}}$	
$f < f_{b32} = \frac{1}{2\pi} \sqrt{\frac{R_b C + R_e C_\pi}{\tau_d R_b C (R_e C_\pi - \tau_d)}}$	
b4 $f < f_{b4} = \frac{1}{2\pi} \sqrt{\frac{1}{[\tau_d (R_e C_\pi - \tau_d) + R_e C_\pi R_b C]^{-1}}}$	
b5 $1 + (R_1 C_1 2\pi f)^2 \gg \frac{R_1}{\frac{g_0 R_b R_e C_\pi}{C_{bc} + C_c} + \frac{R_b C}{C_{bc}}}$	
b6 $f > f_{b61} = \frac{1}{2\pi} \sqrt{\frac{g_0 [R_\pi (C_{bc} + C_c) - R_b C_{bc}] g_{m0} R_\pi + 1)^{-2}}{(C_{bc} + C_c) [L_e (C_{bc} + C_c) + R_e C_\pi R_b C_{bc}]}$	
$f < f_{b62} = \frac{1}{2\pi} \sqrt{\frac{[L_e (C_{bc} + C_c) + R_e C_\pi R_b C_{bc}] [R_e C_\pi - \tau_d]^{-1}}{R_b C (R_e R_b C (C_{bc} + C_c) + R_e C_\pi R_b C_{bc})}}$	
b7 $f < f_{b71} = \frac{1}{2\pi} \sqrt{\frac{[L_e (C_{bc} + C_c) + R_e C_\pi R_b C_{bc} - \tau_d (R_e C_\pi + R_b C - \tau_d)]^{-1}}{[-L_e (C_{bc} + C_c) (g_{m0} R_\pi + 1) + R_\pi C_\pi (R_e C_\pi + R_b C - \tau_d)]^{-1}}}$	
$f < f_{b72} = \frac{1}{2\pi} \sqrt{\frac{(R_e + R_c)(C_{bc} + C_c) + \frac{R_b C_{bc}}{g_{m0} R_\pi + 1}}{R_b C_{bc} R_e C_\pi (R_e C_\pi + R_b C - \tau_d)}}$	
b8 $f < f_{b8} = \frac{1}{2\pi} \sqrt{\frac{1}{(R_b C)^2 + (R_e C_\pi - \tau_d)^2}}$	
b9 $f < f_{b9} = \frac{1}{2\pi} \sqrt{\frac{1}{(R_b C)^2 + (R_e C_\pi - \tau_d)^2}}$	

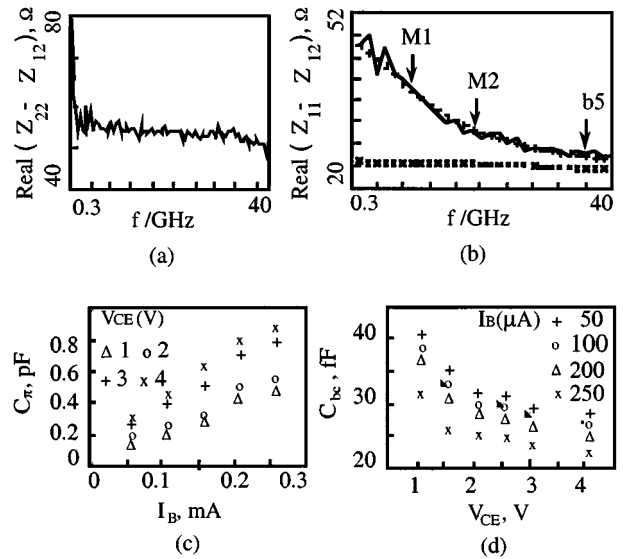


Fig. 2. Determination of: (a), (b) $b1$ and $b5$; R_1 , C_1 (b). $\text{Real}(Z_{11} - Z_{12})$: measured (—), simulated with R_1 , C_1 (+), simulated without R_1 , C_1 (\times). (c), (d) HBTs capacitances versus bias.

$$C_1 = \frac{1}{R_1} \sqrt{\frac{1 - \frac{m_1 - b5}{m_2 - b5}}{(2\pi f_1)^2 \left[\frac{m_1 - b5}{m_2 - b5} - \left(\frac{f_2}{f_1}\right)^2 \right]}} \quad (14)$$

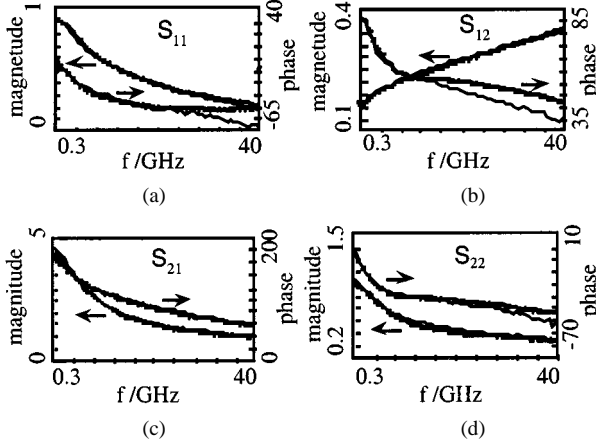


Fig. 3. Measured (—) and simulated (+ + +) S -parameters.

with ($f_1 = 6.652$ GHz, $m_1 = 41.71 \Omega$) and ($f_2 = 19.356$ GHz, $m_2 = 31.25 \Omega$) corresponding to points $M1$ and $M2$, respectively, we have $R_1 = 21.5 \Omega$ and $C_1 = 0.6$ pF.

The resistance R_E is determined using block 8 measured over a low-frequency range $f \ll f_{bs}$ at different emitter currents I_E , such as in [9]. The parasitic inductances are determined from S -parameters measured in a nonconducting state and taking into account the influence of the inductive terms due to certain device parameters that contribute to increase the global inductive effect of the transistor [10].

C. Determination of R_π , g_{m0} , and g_0

R_π is determined from well-known theoretical expression $R_\pi = (N_E V_T)/(I_B)$, and g_{m0} and g_0 are determined using block 7 and block 2, respectively: $g_{m0} = (b7 - 1)/R_\pi$ and $g_0 = b2g_{m0}R_\pi$.

D. Determination of C_π , C_{bc} , R_b , R_c , and τ_d

Expressions of block i ($i = 3-6$) allow us to write the following three nonlinear equations:

$$\frac{ReC_\pi}{C_{bc} + C_c} + \frac{RbC}{C_{bc} + C_c} = b3 \quad (15)$$

$$Rb \left(\frac{C}{C_{bc}} + g_0 \frac{ReC_\pi}{C_{bc} + C_c} \right) = b5 \quad (16)$$

$$\frac{ReC_\pi}{(C_{bc} + C_c)} \frac{RbC_{bc}}{(C_{bc} + C_c)} = \frac{b6 - L_e}{b4} \quad (17)$$

with $x = (C)/C_{bc}$, $y = R_b$, and $Z = (b6 - L_e)/(C_{bc} + C_c)$. Equations (15)–(17) can be rewritten as $Z + xy(1 - x) = b3$, $y = R_b$, $y(x + g_0z) = b5$, $Zy(1 - x) = (b6 - L_e)/b4$, by naming $U = b3$, $V = b5$, and $W = (b6 - L_e)/b4$, we obtain

$$\frac{V}{W^2} z^2 + \left(\frac{1}{W} - \frac{UV}{W^2} \right) z + \left(\frac{V - U}{W} - g_0 \right) = 0. \quad (18)$$

Using physical solution Z^+ of (18) and knowing the different blocks, we have $C_\pi = (Z + b4b7)/R_\pi$, $C_c = ((b4^2 Z^+ (b3 - Z^+))/(b6 - L_e))$, and $C_{bc} = b4 \left[1 - (b4 Z^+ (b3 - Z^+))/(b6 - L_e) \right]$, $R_b = (b6 - L_e)/(b4 Z^+ (1 - (b4 Z^+ (b3 - Z^+))/(b6 - L_e)))$, $R_c = b1 - Z^+$, and $\tau_d = b4b3 - (b9 + L_e)/(Z^+)$

IV. RESULTS AND DISCUSSION

The method is validated by investigating GaInP/GaAs and GaInP/InP HBTs at multibias conditions. The bias variation of the capacitances C_π and C_{bc} , shown in Fig. 2(c) and (d), agrees well with the prevision of physical analysis. The good regularity of the calculated capacitances demonstrates the unicity of the solution. Fig. 3 shows the measured and modeled S -parameters over a frequency range of 0.3–40 GHz. Good agreement in magnitude and phases is obtained. In particular, the evolution versus frequency of all the calculated S -parameters is the same as the measured ones.

V. CONCLUSION

We have demonstrated a new method to directly determine the HBT small-signal equivalent circuit. No use of numerical optimization, nor local fitting routines are required in the procedure. It uses the measured S -parameters to determine independently nine analytical expression blocks, which allow us to calculate the circuit elements. The procedure allows us to determine the base and collector resistances at each bias point with the other bias-dependent elements. In addition to the good agreement obtained between measured and simulated S -parameters of the HBT, the bias dependence of the base-emitter and base-collector capacitances obtained from the proposed multibias extraction procedure agrees well with the prevision of physical analysis.

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